

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	143	wafer with edge same imag\$4 same point	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2004/12/02 17:00
S2	231	wafer with edge same imag\$4 same point	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2004/12/02 17:00
S3	10	wafer with edge same imag\$4 same point same map	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2004/12/02 17:00
S4	10	wafer with edge same imag\$4 same point same map\$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2004/12/02 17:00
S5	274	computer with searchable with database	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2004/12/06 14:00
S6	0	computer with searchable with database same (semiconductor wafer) with reference with information	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2004/12/06 14:01
S7	0	computer with searchable with database same (semiconductor wafer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2004/12/06 14:03
S8	19	computer with searchable with database and (semiconductor wafer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2004/12/06 14:05
S9	18	computer with searchable with database same RAM	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2004/12/06 14:19

S10	50	computer with searchable with database same identif\$6 same information	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2004/12/06 14:37
S11	13	memory with search\$3 with database same (semiconductor wafer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2004/12/06 14:38
S12	13	memory with search\$5 with database same (semiconductor wafer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2004/12/06 14:38
S13	404	(semiconductor wafer) same points same (edge perimeter) and correlat\$4 and (stor\$4 sav\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/05/23 14:35
S14	92	(semiconductor wafer) same points same (edge perimeter) and correlat\$4 same image and (stor\$4 sav\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/05/23 14:38
S15	18	(semiconductor wafer) same points same (edge perimeter) and correlat\$4 same image same points and (stor\$4 sav\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/05/23 14:39
S16	10	(edge perimeter border) with wafer with points and image with correlat\$4 and defect	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/05/26 11:10
S17	0	"00110624.4"	EPO	OR	ON	2005/05/26 11:19
S18	138759	circuit	EPO	OR	ON	2005/05/26 11:19
S19	7715	circuit same semiconductor	EPO	OR	ON	2005/05/26 11:19
S20	429	circuit same semiconductor same wafer	EPO	OR	ON	2005/05/26 11:19
S21	26	circuit same semiconductor same wafer same package	EPO	OR	ON	2005/05/26 11:22
S22	1	"1156309"	EPO	OR	ON	2005/05/26 11:22
S23	512	wafer same (periphery perimeter edge boundary border) same (points areas) and imag\$4 with (points areas) and (stor\$4 sav\$4) with imag\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/05/27 14:17
S24	166	wafer same (periphery perimeter edge boundary border) same (points areas) and imag\$4 with (points areas) and (stor\$4 sav\$4) with imag\$4 and correlat\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/05/27 14:19

S25	32	wafer same (periphery perimeter edge boundary border) same (points areas) and imag\$4 same map with (points areas) and (stor\$4 sav\$4) with imag\$4 and correlat\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/05/27 14:19
S26	18	wafer same (periphery perimeter edge boundary border) same (points areas) same map and imag\$4 with (points areas) and (stor\$4 sav\$4) with imag\$4 and correlat\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/05/27 15:08
S27	2	semiconductor same wafer same (periphery perimeter edge boundary border) same (points areas) same map and imag\$4 with (points areas) and (stor\$4 sav\$4) with imag\$4 and correlat\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/05/27 15:21
S28	21	semiconductor same wafer same (periphery perimeter edge boundary border) same (points areas) and imag\$4 with (points areas) and (stor\$4 sav\$4) with imag\$4 and correlat\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/05/27 15:35
S29	690	wafer with edge with defect	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/05/27 15:35
S30	14	wafer with edge with defect and imag\$4 with correlat\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/05/27 15:35
S31	2154	wafer with edge with points	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/06/09 10:54
S32	73	wafer with edge with points and stor\$4 with image	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/06/09 10:55
S33	20	wafer with edge with points and stor\$4 with image and correlat\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/06/09 10:57

S34	15	wafer with edge with points and stor\$4 with image and correlat\$4 with image	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/06/09 11:00
S35	1	wafer with edge with points and stor\$4 with image and correlat\$4 with image and fake near defect	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/06/09 11:15
S36	7	wafer with edge with points and stor\$4 with image and correlat\$4 with image and defect	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/06/09 12:25
S37	1	fake with defect with map	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/06/09 11:33
S38	43	false with defect with map	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/06/09 11:33
S39	6	false with defect with map and wafer with edge	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/06/09 11:34
S40	71	false with defect and wafer with edge and image	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/06/09 11:35
S41	9	false with defect and wafer with edge and image with correlat\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/06/09 11:36
S42	10	map with point and wafer with edge and image with correlat\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/06/09 12:07
S43	50	map and wafer with edge and image with correlat\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/06/09 12:08

S44	29	map and wafer near edge and image with correlat\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/06/09 12:20
S45	6	map and wafer near edge and image with correlat\$4 and context	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/06/09 12:20
S46	13	wafer near edge and image same predetermined near point	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/06/09 12:44
S47	2	"6799130".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/06/09 12:44